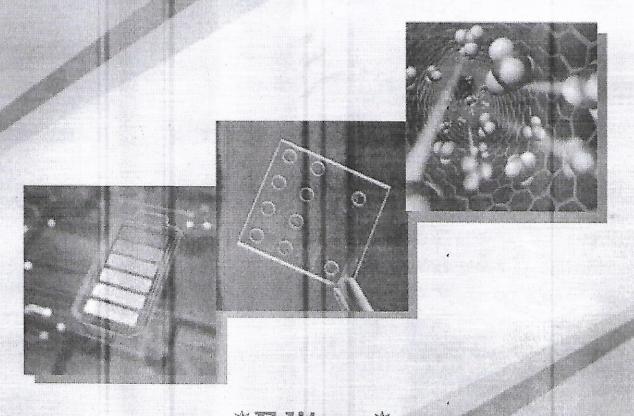
## INNOVATION IN SIMART AND TECHNOMATERIALS



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## PP-77: Structural Properties of Lanthanum Doped Fe<sub>3</sub>O<sub>4</sub> Thin Films

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Abstract: Thin films of Fe<sub>3</sub>O<sub>4</sub> and lanthanum doped Fe<sub>3</sub>O<sub>4</sub> nanomaterials were prepared by well known SILAR method. X-ray diffraction (XRD) and Fourier Transform Infrared Spectroscopy (FTIR) tools were used to characterize the nanomaterials. The presence of (220), (311), (400),(422),(511) and (440) planes in X- ray diffraction patterns of Fe<sub>3</sub>O<sub>4</sub> and lanthanum doped Fe<sub>3</sub>O<sub>4</sub> confirms the formation of cubic spinal structure without any ambiguity peak. Lattice constant of lanthanum doped Fe<sub>3</sub>O<sub>4</sub> nanomaterial becomes lower whereas its crystallite size becomes higher than that of Fe<sub>3</sub>O<sub>4</sub> nanomaterials. The presence of required absorption bands corresponding to Fe<sub>3</sub>O<sub>4</sub> nanomaterials in the Fourier Transformation Infrared Spectra also confirms the formation of single cubic spinal structure. The absorption bands observed at 669cm<sup>-1</sup>, 854cm<sup>-1</sup>, 1020 cm<sup>-1</sup> and 1463 cm<sup>-1</sup> may be due to stretching vibration of La-O bond.

Keywords: Fe<sub>3</sub>O<sub>4</sub> nanomaterial thin films; SILAR Method; XRD; FTIR.